

## Deutsche Akkreditierungsstelle GmbH

### Annex to the Accreditation Certificate D-PL-17283-01-00 according to DIN EN ISO/IEC 17025:2018

Valid from: 11.02.2021

Date of issue: 11.02.2021

Holder of certificate:

**TASCON Gesellschaft für Oberflächen- und Materialcharakterisierung mbH**  
**Mendelstraße 17, 48149 Münster**

Tests in the fields:

physical-chemical analysis of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities and near-surface volume material, including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids and paints by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS); determination of the roughness of surfaces by means of Optical Profilometry

Within the given testing field marked with \*\* the testing laboratory is permitted, without being required to inform and obtain prior approval from DAkkS, the modification and refinement of testing methods. The listed testing methods are exemplary.

The testing laboratory maintains a current list of all testing procedures within the flexible scope of accreditation.

Within the scope of accreditation marked with \*\*\*, the testing laboratory is permitted, without being to inform and obtain prior approval from DAkkS, to use standards or equivalent testing methods listed here with different issue dates. The testing laboratory maintains a current list of all testing procedures within the flexible scope of accreditation.

*The management system requirements of DIN EN ISO/IEC 17025 are written in the language relevant to the operations of testing laboratories. Laboratories that conform to the requirements of this standard, operate generally in accordance with the principles of DIN EN ISO 9001.*

*The certificate together with the annex reflects the status as indicated by the date of issue.*

*The current status of any given scope of accreditation may be found respectively in the database of accredited bodies of Deutsche Akkreditierungsstelle GmbH <https://www.dakks.de/en/content/accredited-bodies-dakks>.*

**1 Determination of the chemical, elemental and molecular composition of surfaces, interfaces, near-surface layers, complex layer systems, trace impurities and near-surface volume material, including the lateral and depth distribution on solids, cross sections, powders, particles, fibres, liquids and paints by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS) \*\***

VA-OG-AM-ToF-SIMS-Spektrenakquisition / 3 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Spectrometry
VA-OG-AM-ToF-SIMS-Imageakquisition / 3 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Imaging
VA-OG-AM-ToF-SIMS-Tiefenprofilakquisition / 2 2017-02	Chemical characterisation of surfaces by means of Time-of-Flight Secondary Ion Mass Spectrometry (ToF-SIMS): Depth Profiling
VA-OG-AB-ToF-SIMS-Quantifizierung-von-B-in-Si / 2 2017-02	Quantitative Detection of Boron in Silicon (ToF-SIMS)

**2 Determination of the roughness of surfaces by means of Optical Profilometry \*\*\***

DIN EN ISO 4287 2010-07	Geometrical Product Specifications (GPS) - Surface texture: Profile method - Terms, definitions and surface texture parameters
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**abbreviations used:**

DIN	German Institute for Standardization
EN	European Standard
ISO	International Organization for Standardization
VA-...	Procedural instructions for in-house procedures of TASCON GmbH